MC74VHC1GT14

Schmitt-Trigger Inverter / CMOS Logic Level Shifter

LSTTL−Compatible Inputs

The MC74VHC1GT14 is a single gate CMOS Schmitt−trigger inverter fabricated with silicon gate CMOS technology. It achieves high speed operation similar to equivalent Bipolar Schottky TTL while maintaining CMOS low power dissipation.

The internal circuit is composed of three stages, including a buffer output which provides high noise immunity and stable output.

The device input is compatible with TTL−type input thresholds and the output has a full 5 V CMOS level output swing. The input protection circuitry on this device allows overvoltage tolerance on the input, allowing the device to be used as a logic−level translator from 3 V CMOS logic to 5 V CMOS Logic or from 1.8 V CMOS logic to 3 V CMOS Logic while operating at the high−voltage power supply.

The MC74VHC1GT14 input structure provides protection when voltages up to 7 V are applied, regardless of the supply voltage. This allows the MC74VHC1GT14 to be used to interface 5 V circuits to 3 V circuits. The output structures also provide protection when $V_{CC} = 0$ V. These input and output structures help prevent device destruction caused by supply voltage − input/output voltage mismatch, battery backup, hot insertion, etc. The MC74VHC1GT14 can be used to enhance noise immunity or to square up slowly changing waveforms.

Features

- High Speed: t_{PD} = 4.5 ns (Typ) at V_{CC} = 5 V
- Low Power Dissipation: I_{CC} = 1 μA (Max) at T_A = 25°C
- TTL−Compatible Inputs: V_{IL} = 0.8 V; V_{IH} = 2 V
- CMOS−Compatible Outputs: $V_{OH} > 0.8\ V_{CC}$; $V_{OL} < 0.1\ V_{CC}$ @Load
- Power Down Protection Provided on Inputs and Outputs
- Balanced Propagation Delays
- Pin and Function Compatible with Other Standard Logic Families
- Chip Complexity: FETs = 100; Equivalent Gates = 25
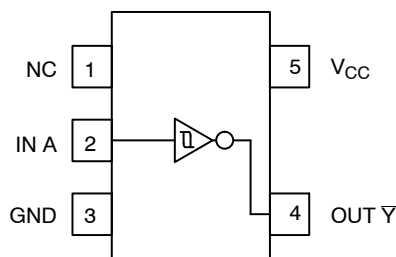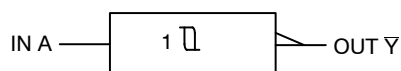- These Devices are Pb−Free and are RoHS Compliant

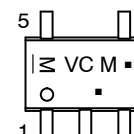**Figure 1. Pinout** (Top View)

Figure 2. Logic Symbol
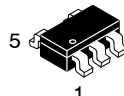
ON Semiconductor®

MARKING DIAGRAMS

SC−88A / SC70−5 / SOT−353
DF SUFFIX
CASE 419A

TSOP−5 / SOT23−5 / SC59−5
DT SUFFIX
CASE 483
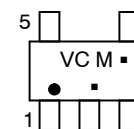
VC = Device Code
M = Date Code*
▪ = Pb−Free Package

(Note: Microdot may be in either location)
*Date Code orientation and/or position may vary depending upon manufacturing location.

PIN ASSIGNMENT

1	NC
2	IN A
3	GND
4	OUT $\overline{Y}$
5	V_{CC}

FUNCTION TABLE

A Input	$\overline{Y}$ Output
L	H
H	L

ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 4 of this data sheet.

MAXIMUM RATINGS

Symbol	Characteristics		Value	Unit
V_{CC}	DC Supply Voltage		−0.5 to +7.0	V
V_{IN}	DC Input Voltage		−0.5 to +7.0	V
V_{OUT}	DC Output Voltage	$V_{CC} = 0$ High or Low State	−0.5 to 7.0 −0.5 to V_{CC} + 0.5	V
I_{IK}	Input Diode Current		−20	mA
I_{OK}	Output Diode Current	$V_{OUT} <$ GND; $V_{OUT} > V_{CC}$	+20	mA
I_{OUT}	DC Output Current, per Pin		+25	mA
I_{CC}	DC Supply Current, V_{CC} and GND		+50	mA
P_D	Power Dissipation in Still Air	SC−88A, TSOP−5	200	mW
θ_{JA}	Thermal Resistance	SC−88A, TSOP−5	333	°C/W
T_L	Lead Temperature, 1 mm from Case for 10 secs		260	°C
T_J	Junction Temperature Under Bias		+150	°C
T_{stg}	Storage Temperature		−65 to +150	°C
V_{ESD}	ESD Withstand Voltage	Human Body Model (Note 1) Machine Model (Note 2) Charged Device Model (Note 3)	> 2000 > 200 N/A	V
$I_{Latchup}$	Latchup Performance	Above V_{CC} and Below GND at 125°C (Note 4)	±500	mA

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.
1. Tested to EIA/JESD22−A114−A
2. Tested to EIA/JESD22−A115−A
3. Tested to JESD22−C101−A
4. Tested to EIA/JESD78

RECOMMENDED OPERATING CONDITIONS

Symbol	Characteristics		Min	Max	Unit
V_{CC}	DC Supply Voltage		3.0	5.5	V
V_{IN}	DC Input Voltage		0.0	5.5	V
V_{OUT}	DC Output Voltage	$V_{CC} = 0$ High or Low State	0.0 0.0	5.5 V_{CC}	V
T_A	Operating Temperature Range		−55	+125	°C
t_r , t_f	Input Rise and Fall Time	$V_{CC} = 3.3$ V $\pm$ 0.3 V $V_{CC} = 5.0$ V $\pm$ 0.5 V	− −	No Limit No Limit	ns/V

**Device Junction Temperature versus
Time to 0.1% Bond Failures**

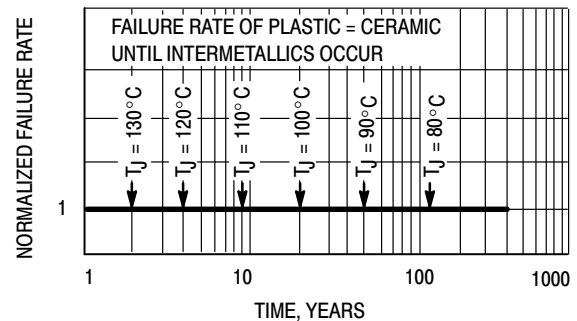| Junction Temperature °C	Time, Hours	Time, Years
80	1,032,200	117.8
90	419,300	47.9
100	178,700	20.4
110	79,600	9.4
120	37,000	4.2
130	17,800	2.0
140	8,900	1.0

Figure 3. Failure Rate vs. Time Junction Temperature

MC74VHC1GT14

DC ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Test Conditions	V_{CC} (V)	$T_A = 25°C$ Min	$T_A = 25°C$ Typ	$T_A = 25°C$ Max	$T_A \leq 85°C$ Min	$T_A \leq 85°C$ Max	$-55 \leq T_A \leq 125°C$ Min	$-55 \leq T_A \leq 125°C$ Max	Unit
V_{T+}	Positive Threshold Voltage		3.0 4.5 5.5	1.20 1.58 1.79	1.40 1.74 1.94	1.60 2.00 2.10	 	1.6 2.0 2.0	 	1.6 2.0 2.0	V
V_{T-}	Negative Threshold Voltage		3.0 4.5 5.5	0.35 0.5 0.6	0.76 1.01 1.13	0.93 1.18 1.29	0.35 0.5 0.6	 	0.35 0.5 0.6	 	V
V_H	Hysteresis Voltage		3.0 4.5 5.5	0.30 0.40 0.50	0.64 0.73 0.81	1.20 1.40 1.60	0.30 0.40 0.50	1.20 1.40 1.60	0.30 0.40 0.50	1.20 1.40 1.60	V
V_{OH}	Minimum High–Level Output Voltage	$V_{IN} \leq V_T -$ Min $I_{OH} = -50\ \mu A$	2.0 3.0 4.5	1.9 2.9 4.4	2.0 3.0 4.5		1.9 2.9 4.4		1.9 2.9 4.4		V
		$I_{OH} = -4$ mA $I_{OH} = -8$ mA	3.0 4.5	2.58 3.94			2.48 3.80		2.34 3.66		V
V_{OL}	Maximum Low–Level Output Voltage	$V_{IN} \geq V_T +$ Max $I_{OL} = 50\ \mu A$	2.0 3.0 4.5		0.0 0.0 0.0	0.1 0.1 0.1		0.1 0.1 0.1		0.1 0.1 0.1	V
		$I_{OL} = 4$ mA $I_{OL} = 8$ mA	3.0 4.5			0.36 0.36		0.44 0.44		0.52 0.52	V
I_{IN}	Maximum Input Leakage Current	$V_{IN} = 5.5$ V or GND	0 to 5.5			±0.1		±1.0		±1.0	μA
I_{CC}	Maximum Quiescent Supply Current	$V_{IN} = V_{CC}$ or GND	5.5			1.0		20		40	μA
I_{CCT}	Quiescent Supply Current	Input: $V_{IN} = 3.4$ V	5.5			1.35		1.50		1.65	mA
I_{OPD}	Output Leakage Current	$V_{OUT} = 5.5$ V	0.0			0.5		5.0		10	μA

AC ELECTRICAL CHARACTERISTICS $C_{load} = 50$ pF, Input $t_r/t_f = 3.0$ ns

Symbol	Parameter	Test Conditions		$T_A = 25°C$ Min	$T_A = 25°C$ Typ	$T_A = 25°C$ Max	$T_A \leq 85°C$ Min	$T_A \leq 85°C$ Max	$-55 \leq T_A \leq 125°C$ Min	$-55 \leq T_A \leq 125°C$ Max	Unit
t_{PLH}, t_{PHL}	Maximum Propagation Delay, A to $\overline{Y}$	$V_{CC} = 3.3 \pm 0.3$ V	$C_L = 15$ pF $C_L = 50$ pF		7.0 8.4	12.8 16.3	1.0 1.0	15.0 18.5	1.0 1.0	17.0 20.5	ns
		$V_{CC} = 5.0 \pm 0.5$ V	$C_L = 15$ pF $C_L = 50$ pF		4.5 5.8	8.6 10.6	1.0 1.0	10.0 12.0	1.0 1.0	11.5 13.5	
C_{IN}	Maximum Input Capacitance				5	10		10		10	pF

		Typical @ 25°C, $V_{CC} = 5.0$ V	
C_{PD}	Power Dissipation Capacitance (Note 5)	10	pF

5. C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation: $I_{CC(OPR)} = C_{PD} \bullet V_{CC} \bullet f_{in} + I_{CC}$. C_{PD} is used to determine the no–load dynamic power consumption; $P_D = C_{PD} \bullet V_{CC}^2 \bullet f_{in} + I_{CC} \bullet V_{CC}$.
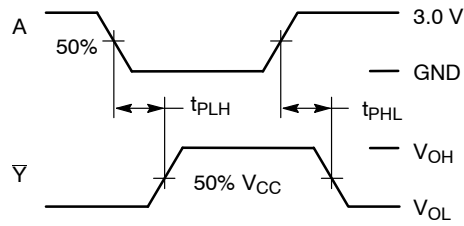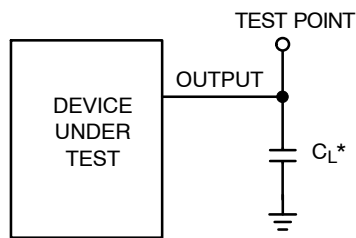
MC74VHC1GT14

Figure 4. Switching Waveforms

*Includes all probe and jig capacitance

Figure 5. Test Circuit

ORDERING INFORMATION

Device	Package	Shipping†
M74VHC1GT14DFT1G	SC70−5/SC−88A/SOT−353 (Pb−Free)	3000/Tape & Reel
M74VHC1GT14DFT2G	SC70−5/SC−88A/SOT−353 (Pb−Free)	
M74VHC1GT14DTT1G	SOT23−5/TSOP−5/SC59−5 (Pb−Free)	

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

PACKAGE DIMENSIONS

SC−88A (SC−70−5/SOT−353)
CASE 419A−02
ISSUE K
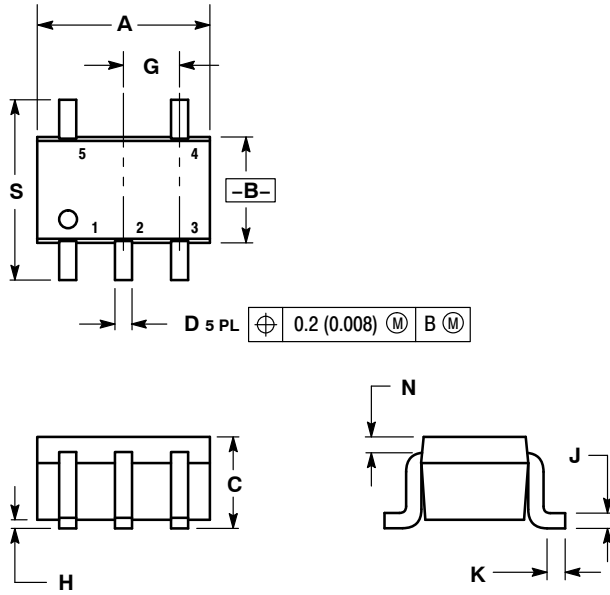
NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: INCH.
3. 419A−01 OBSOLETE. NEW STANDARD 419A−02.
4. DIMENSIONS A AND B DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	0.071	0.087	1.80	2.20
B	0.045	0.053	1.15	1.35
C	0.031	0.043	0.80	1.10
D	0.004	0.012	0.10	0.30
G	0.026 BSC		0.65 BSC	
H	---	0.004	---	0.10
J	0.004	0.010	0.10	0.25
K	0.004	0.012	0.10	0.30
N	0.008 REF		0.20 REF	
S	0.079	0.087	2.00	2.20

PACKAGE DIMENSIONS

TSOP–5
CASE 483–02
ISSUE H
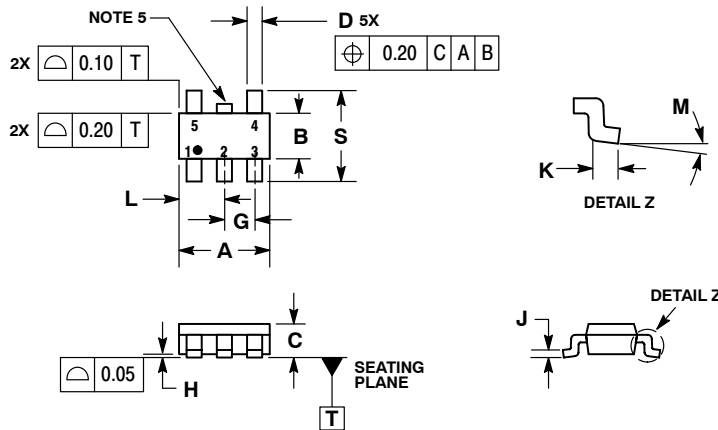
NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: MILLIMETERS.
3. MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH THICKNESS. MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS OF BASE MATERIAL.
4. DIMENSIONS A AND B DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.
5. OPTIONAL CONSTRUCTION: AN ADDITIONAL TRIMMED LEAD IS ALLOWED IN THIS LOCATION. TRIMMED LEAD NOT TO EXTEND MORE THAN 0.2 FROM BODY.

| DIM | MILLIMETERS | |
	MIN	MAX
A	3.00 BSC	
B	1.50 BSC	
C	0.90	1.10
D	0.25	0.50
G	0.95 BSC	
H	0.01	0.10
J	0.10	0.26
K	0.20	0.60
L	1.25	1.55
M	0 °	10 °
S	2.50	3.00

SOLDERING FOOTPRINT*

$\frac{1.9}{0.074}$

$\frac{0.95}{0.037}$

$\frac{2.4}{0.094}$

$\frac{1.0}{0.039}$

$\frac{0.7}{0.028}$

SCALE 10:1 $\left(\frac{mm}{inches}\right)$
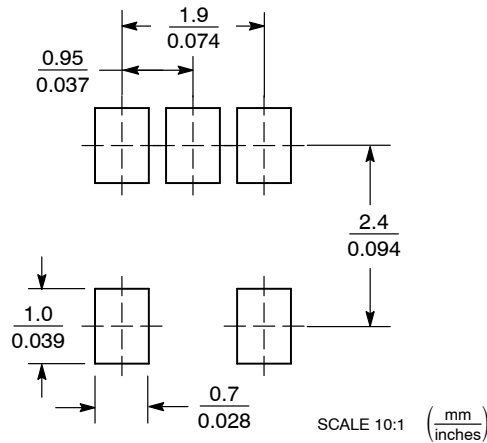
*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.